

Search Notes

Application/Control No.

10/715,031

Examiner

Teena Mitchell

Applicant(s)/Patent under
Reexamination

E. ZAISER ET AL.

Art Unit

3771

SEARCHED

Class	Subclass	Date	Examiner
128	201.21 201.26 202.27 203.21		
	203.24 204.18		
	204.25 205.24		
	205.22 203.24		
	204.29		
137	505.25 505		
	505.26 567		
251	368		

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner